

April 1988 Revised August 1999

## 74F521

# **8-Bit Identity Comparator**

### **General Description**

The 74F521 is an expandable 8-bit comparator. It compares two words of up to eight bits each and provides a LOW output when the two words match bit for bit. The expansion input  $\overline{I}_{A=B}$  also serves as an active LOW enable input.

#### **Features**

- Compares two 8-bit words in 6.5 ns typ
- Expandable to any word length
- 20-pin package

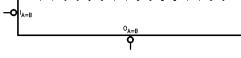
## **Ordering Code:**

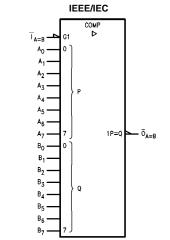
Order Number	Package Number	Package Description
74F521SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F521SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F521MSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74F521PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

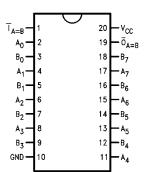
## **Logic Symbols**







# **Connection Diagram**



# **Unit Loading/Fan Out**

Pin Names	D. c. colinstico	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>	
	Description	HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>	
A <sub>0</sub> -A <sub>7</sub>	Word A Inputs	1.0/1.0	20 μA/-0.6 mA	
B <sub>0</sub> -B <sub>7</sub>	Word B Inputs	1.0/1.0	20 μA/-0.6 mA	
$\bar{I}_{A=B}$	Expansion or Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
$\overline{O}_{A=B}$	Identity Output (Active LOW)	50/33.3	-1 mA/20 mA	

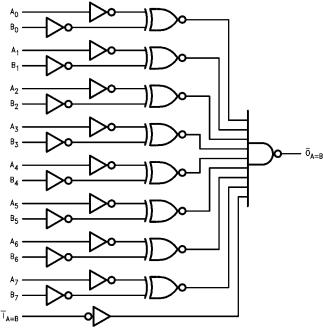
# **Truth Table**

In	Output			
Ī <sub>A = B</sub>	$\bar{I}_{A=B}$ A, B			
L	A = B (Note 1)	L		
L	$A \neq B$	Н		
Н	A = B (Note 1)	Н		
Н	$A \neq B$	Н		

H = HIGH Voltage Level L = LOW Voltage Level

**Note 1:**  $A_0 = B_0$ ,  $A_1 = B_1$ ,  $A_2 = B_2$ , etc.

# **Logic Diagram**



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

## Absolute Maximum Ratings(Note 2)

-65°C to +150°C Storage Temperature Ambient Temperature under Bias -55°C to +125°C

Junction Temperature under Bias -55°C to +150°C V<sub>CC</sub> Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 3) -0.5V to +7.0VInput Current (Note 3) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with  $V_{CC} = 0V$ )

Standard Output -0.5V to  $V_{CC}$ 

3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated  $I_{OL}$  (mA)

## **Recommended Operating Conditions**

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 2: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 3: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

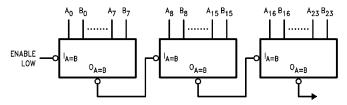
Symbol	Parameter		Min	Тур	Max	Units	v <sub>cc</sub>	Conditions	
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal	
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized as a LOW Signal	
$V_{CD}$	Input Clamp Diode Voltage				-1.2	V	Min	I <sub>IN</sub> = -18 mA	
V <sub>OH</sub>	Output HIGH	10% V <sub>CC</sub>	2.5			V	Min	I <sub>OH</sub> = -1 mA	
	Voltage	5% V <sub>CC</sub>	2.7					$I_{OH} = -1 \text{ mA}$	
V <sub>OL</sub>	Output LOW	10% V <sub>CC</sub>			0.5	V	Min	I <sub>OL</sub> = 20 mA	
	Voltage								
I <sub>IH</sub>	Input HIGH Current				5.0	μΑ	Max	V <sub>IN</sub> = 2.7V	
I <sub>BVI</sub>	Input HIGH Current				7.0	μА	Max	V -70V	
	Breakdown Test	akdown Test			7.0			V <sub>IN</sub> = 7.0V	
I <sub>CEX</sub>	Output HIGH	Output HIGH			50		May	V V	
	Leakage Current				50	μΑ	Max	$V_{OUT} = V_{CC}$	
V <sub>ID</sub>	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu A$	
	Test		4.75			V	0.0	All Other Pins Grounded	
I <sub>OD</sub>	Output Leakage Circuit Current				0.75	μА	0.0	V <sub>IOD</sub> = 150 mV	
					3.75			All Other Pins Grounded	
I <sub>IL</sub>	Input LOW Current				-0.6	mA	Max	$V_{IN} = 0.5V$	
Ios	Output Short-Circuit Current		-60		-150	mA	Max	V <sub>OUT</sub> = 0V	
I <sub>CCH</sub>	Power Supply Curre	nt		21	32	mA	Max	V <sub>O</sub> = HIGH	

# **AC Electrical Characteristics**

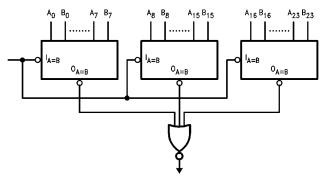
Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_{A} = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		$T_{A} = 0^{\circ}C \text{ to } +70^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	3.0	7.0	10.0	3.0	14.0	3.0	11.0	ns
t <sub>PHL</sub>	$A_n$ or $B_n$ to $\overline{O}_{A=B}$	4.5	7.0	10.0	4.0	15.0	4.0	11.0	
t <sub>PLH</sub>	Propagation Delay	3.0	5.0	6.5	3.0	8.5	3.0	7.5	
t <sub>PHL</sub>	$\overline{I}_{A=B}$ to $\overline{O}_{A=B}$	3.5	6.5	9.0	3.5	13.5	3.5	10.0	ns

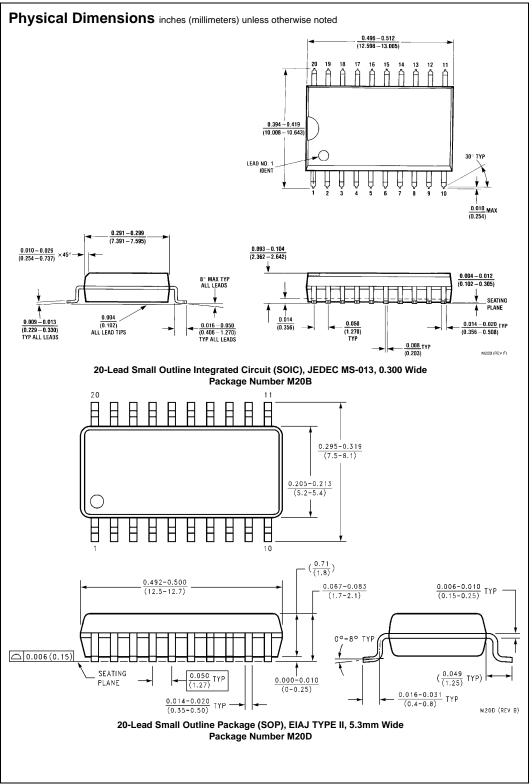
# **Applications**

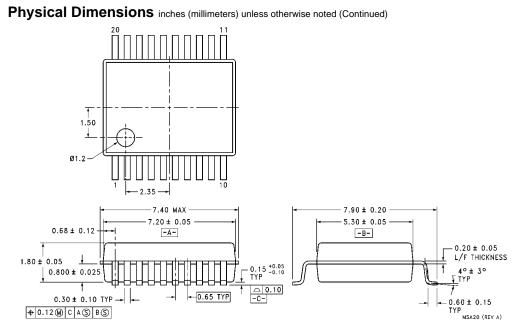
#### Ripple Expansion



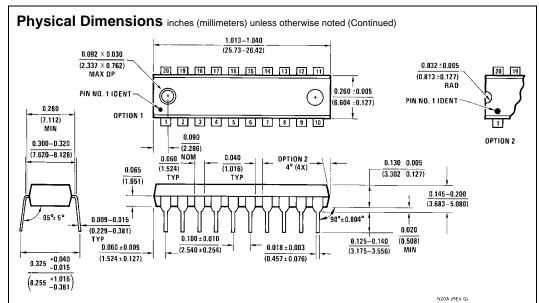
#### Parallel Expansion







20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide Package Number MSA20



20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N20A

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